Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/748,229	KIM ET AL.	
Examiner	Art Unit	
Devin Hanan	3745	

Devin Hanan

SEARCHED				
Class	Subclass	Date	Examiner	
415	58.4			
	58.2-58.3			
	228			
416	181			
	185			
	186R			
	188			
417	423.1			
	370	9/15/2005	DH	
	,			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH N (INCLUDING SEAR)
	DATE	EXMR
consulted Chris Verdier class 415 and 416	9/14/2005	DH
consulted Chuch Freay class 417	9/15/2005	DH
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